

68XX Microcontroller Family Compatible

256K

X68257

32,768 x 8 Bit

E² Micro-Peripheral

FEATURES

- Multiplexed Address/Data Bus —Direct Interface to Popular 68HC11 Family
- High Performance CMOS
- -Fast Access Time, 120ns
- -Low Power
 - -60mA Active Maximum
- -500µA Standby Maximum
- Software Data Protection
- Toggle Bit Polling —Early End of Write Detection
- Page Mode Write

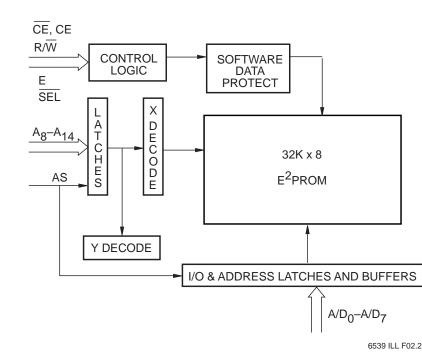
 Allows up to 128 Bytes to be Written in One Write Cycle
- High Reliability

 Endurance: 10,000 Write Cycle
 Data Retention: 100 Years
- 28-Lead PDIP Package
- 28-Lead SOIC Package
- 32-Lead PLCC Package

FUNCTIONAL DIAGRAM

DESCRIPTION

The X68257 is an 32K x 8 E²PROM fabricated with advanced CMOS Textured Poly Floating Gate Technology. The X68257 features a multiplexed address and data bus allowing direct interface to a variety of popular single-chip microcontrollers operating in expanded multiplexed mode without the need for additional interface circuitry.



PIN DESCRIPTIONS

Address/Data (A/D₀-A/D₇)

Multiplexed low-order addresses and data. The addresses flow into the device while AS is HIGH. After AS transitions from a HIGH to LOW the addresses are latched. Once the addresses are latched these pins input data or output data depending on R/\overline{W} , \overline{SEL} , and CE.

Addresses (A₈-A₁₄)

High order addresses flow into the device when AS = V_{IH} and are latched when AS goes LOW.

Chip Enable (CE)

The Chip Enable input must be LOW to enable all read/ write operations. When \overline{CE} is HIGH, AS is LOW, and CE is LOW, the X68257 is placed in the low power standby mode.

Chip Enable (CE)

Chip Enable is active HIGH. When CE is used to select the device, the CE must be tied HIGH.

Program Store Enable (SEL)

When the X68257 is to be used in a 68XX-based system, $\overline{\text{SEL}}$ is tied to $\text{V}_{\text{SS}}.$

Read/Write (R/W)

When the X68257 is to be used in a 68XX-based system, R/\overline{W} is tied directly to the microcontroller's R/\overline{W} output.

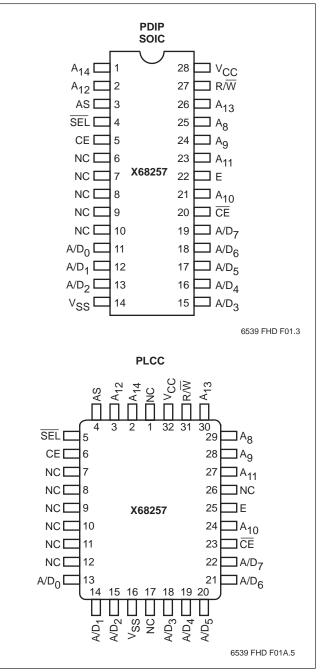
Address Strobe (AS)

Addresses flow through the latches to address decoders when AS is HIGH and are latched when AS transitions from a HIGH to LOW.

PIN NAMES

Symbol	Description
AS	Address Strobe
A/D ₀ A/D ₇	Address Inputs/Data I/O
A ₈ -A ₁₄	Address Inputs
E	Enable Input
R/W	Read/Write Input
CE, CE	Chip Enable
SEL	Device Select—Connect to Vss
Vss	Ground
Vcc	Supply Voltage
NC	No Connect
	6539 PGM T01.2

PIN CONFIGURATION



PRINCIPLES OF OPERATION

The X68257 is a highly integrated peripheral device for a wide variety of single-chip microcontrollers. The X68257 provides 32K-bytes of 5V E²PROM which can be used either for program storage, data storage, or a combination of both, in systems based upon Von Neumann (68XX) architectures. The X68257 incorporates the interface circuitry normally needed to decode the control signals and demultiplex the address/data bus to provide a "seamless" interface.

The interface inputs on the X68257 are configured such that it is possible to directly connect them to the proper interface signals of the appropriate single-chip micro-controller.

The X68257 features the industry standard 5V E²PROM characteristics such as byte or page mode write and Toggle Bit Polling.

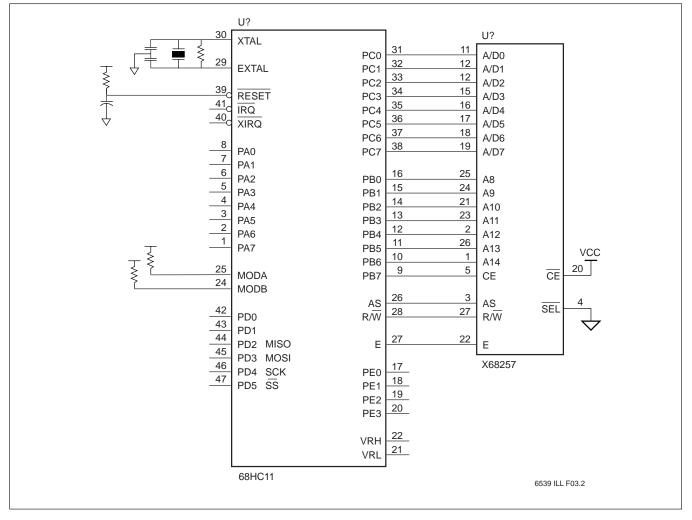
DEVICE OPERATION

Motorola 68XX operation requires the microcontroller AS, E, and R/\overline{W} outputs to be tied to the X68257 AS, E, and R/\overline{W} inputs respectively.

The falling edge of AS will latch the addresses for both a read and write operation. The state of the R/\overline{W} output determines the operation to be performed, with the E signal acting as a data strobe.

If R/\overline{W} is HIGH and CE is HIGH (read operation) data will be output on $A/D_0-A/D_7$ after E transitions HIGH. If R/\overline{W} is LOW and CE is HIGH (write operation) data present at $A/D_0-A/D_7$ will be strobed into the X68257 on the HIGH to LOW transition of E.

Typical Application



X68257

CE	Е	R/₩	Mode	I/O	Power
V _{SS}	Х	Х	Standby	High Z	Standby (CMOS)
LOW	Х	Х	Standby	High Z	Standby (TTL)
HIGH	HIGH	HIGH	Read	Dout	Active
HIGH	A	LOW	Write	D _{IN}	Active

MODE SELECTION

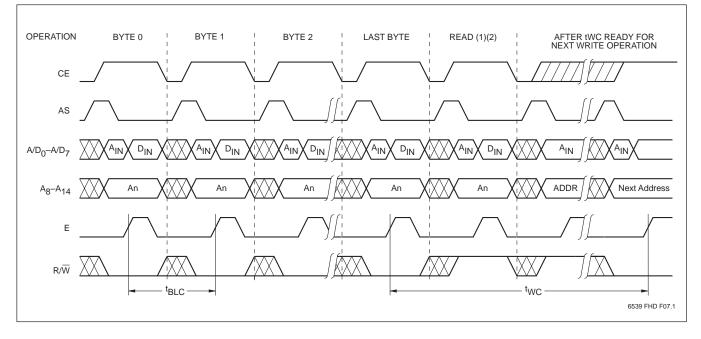
6539 PGM T02.2

PAGE WRITE OPERATION

Regardless of the microcontroller employed, the X68257 supports page mode write operations. This allows the microcontroller to write from 1 to 128 bytes of data to the X68257. Each individual write within a page write operation must conform to the byte write timing requirements.

The rising edge of E starts a timer delaying the internal programming cycle $100\mu s$. Therefore, each successive write operation must begin within $100\mu s$ of the last byte written. The following waveforms illustrate the sequence and timing requirements.

Page Write Timing Sequence for E Controlled Operation



Note: (1) For each successive write within a page write cycle $A_7 - A_{14}$ must be the same.

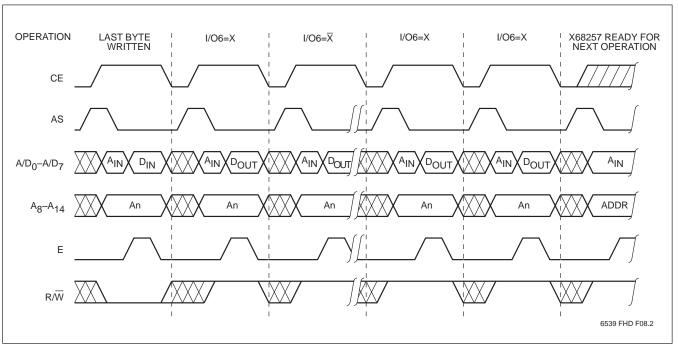
X68257

Toggle Bit Polling

Because the typical write timing is less than the specified 5ms, Toggle Bit Polling has been provided to determine the early end of write. During the internal programming cycle I/O_6 will toggle from "1" to "0" and "0" to "1" on

subsequent attempts to read the device. When the internal cycle is complete, the toggling will cease and the device will be accessible for additional read or write operations.

Toggle Bit Polling E Control

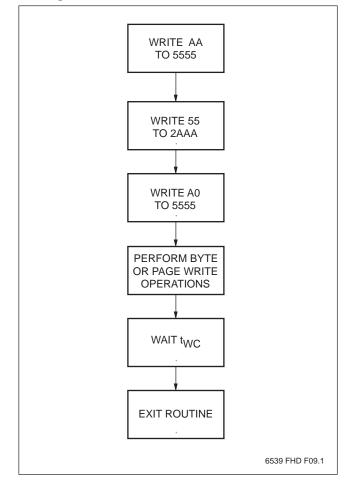


Software Data Protection

Software Data Protection (SDP) is employed to protect the entire array against inadvertent writes. To write to the X68257, a three-byte command sequence must precede the byte(s) being written.

All write operations, both the command sequence and any data write operations must conform to the page write timing requirements.

Writing with SDP



SYMBOL TABLE

ABSOLUTE MAXIMUM RATINGS*

Temperature under Bias –65°C to +135°C
Storage Temperature –65°C to +150°C
Voltage on any Pin with
Respect to V _{SS} 1V to +7V
D.C. Output Current5mA
Lead Temperature
(Soldering, 10 seconds) 300°C

*COMMENT

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and the functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

Temperature	Min.	Max.
Commercial	0°C	+70°C
Industrial	-40°C	+85°C
Military	−55°C	+125°C
		6539 PGM T03.1

Supply Voltage	Limits
X68257	5V ±10%
	6539 PGM T04.1

D.C. OPERATING CHARACTERISTICS (Over recommended operating conditions unless otherwise specified.)

		Lin	nits		
Symbol	Parameter	Min.	Max.	Units	Test Conditions
Icc	V _{CC} Current (Active)		60	mA	$CE = V_{IL}$, All I/O's = Open, Other Inputs = V _{CC} , AS = V _{IH}
I _{SB1} (CMOS)	V _{CC} Current (Standby)		500	μΑ	$CE = V_{SS}$, All I/O's = Open,Other Inputs = $V_{CC} - 0.3V$, AS = V_{SS}
ISB2(TTL)	V _{CC} Current (Standby)		6	mA	CE = V _{IH} , All I/O's = Open, Other Inputs = V _{IH} , AS = V _{IL}
ILI	Input Leakage Current		10	μΑ	$V_{IN} = V_{SS}$ to V_{CC}
ILO	Output Leakage Current		10	μΑ	$V_{OUT} = V_{SS}$ to V_{CC} , $E = V_{IL}$
V _{IL} (1)	Input LOW Voltage	-1	0.8	V	
VIH ⁽¹⁾	Input HIGH Voltage	2	V _{CC} + 0.5	V	
Vol	Output LOW Voltage		0.4	V	$I_{OL} = 2.1 \text{mA}$
Voh	Output HIGH Voltage	2.4		V	Іон = -400μА
					6539 PGM T05.1

CAPACITANCE $T_A = +25^{\circ}C$, f = 1MHz, $V_{CC} = 5V$

Symbol	Test	Max.	Units	Conditions
C _{I/O} (2)	Input/Output Capacitance	10	pF	$V_{I/O} = 0V$
CIN ⁽²⁾	Input Capacitance	6	pF	$V_{IN} = 0V$
				6539 PGM T0

POWER-UP TIMING

Symbol	Parameter	Max.	Units
t _{PUR} (2)	Power-Up to Read	1	ms
t _{PUW} (2)	Power-Up to Write	5	ms
			6539 PGM T07

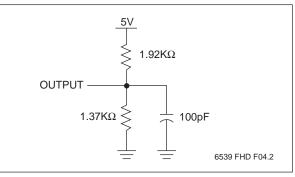
Notes: (1) V_{IL} min. and V_{IH} max. are for reference only and are not tested. (2) This parameter is periodically sampled and not 100% tested.

A.C. CONDITIONS OF TEST

Input Pulse Levels	0V to 3V
Input Rise and	
Fall Times	10ns
Input and Output	
Timing Levels	1.5V

6539 PGM T08.1

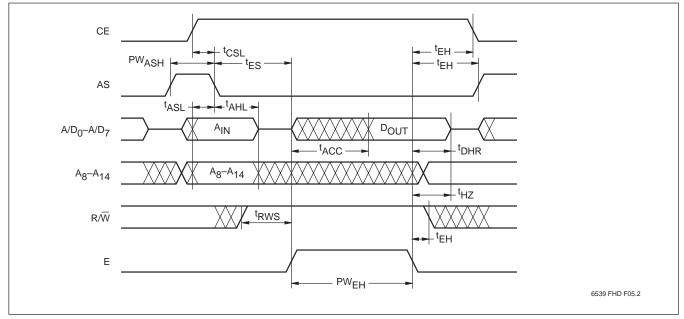
TEST CIRCUIT



A.C. CHARACTERISTICS (Over the recommended operating conditions unless otherwise specified.) E Controlled Read Cycle

Symbol	Parameter	Min.	Max.	Units
PWASH	Address Strobe Pulse Width	80		ns
tasl	Address Setup Time	20		ns
tAHL	Address Hold Time	30		ns
tacc	Data Access Time		120	ns
tDHR	Data Hold Time	0		ns
tcsL	CE Setup Time	7		ns
РWeн	E Pulse Width	150		ns
t _{ES}	Enable Setup Time	30		ns
teh	E Hold Time	20		ns
tRWS	R/W Setup Time	20		ns
t _{HZ} (3)	E LOW to High Z Output		50	ns
t _{LZ} (3)	E HIGH to Low Z Output	0		ns

E Controlled Read Cycle

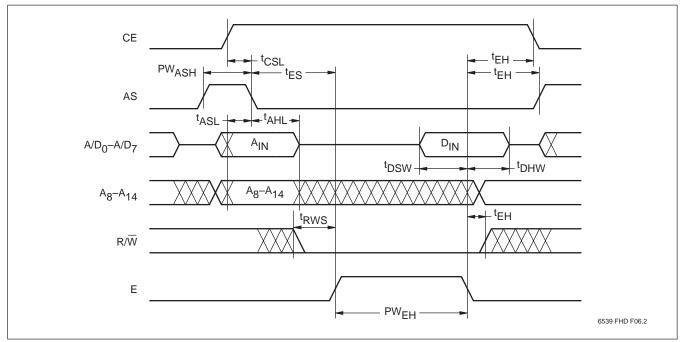




E Controlled Write Cycle

Symbol	Parameter	Min.	Max.	Units
PWASH	Address Strobe Pulse Width	80		ns
tASL	Address Setup Time	20		ns
t _{AHL}	Address Hold Time	30		ns
tDSW	Data Setup Time	50		ns
tDHW	Data Hold Time	30		ns
tcsL	CE Setup Time	7		ns
PWEH	E Pulse Width	120		ns
twc	Write Cycle Time		5	ms
tes	Enable Setup Time	30		ns
t _{RWS}	R/W Setup Time	20		ns
teh 6539 FHD F05.2	E Hold Time	20		ns
	Byte Load Time (Page Write)	0.5	100	μs
tBLC	Byte Load Time (Page Write)	0.5		100

E Controlled Write Cycle

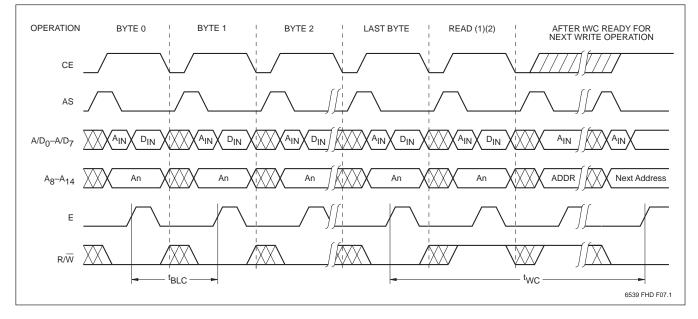


Note: (4) t_{WC} is the minimum cycle time to be allowed from the system perspective unless polling techniques are used. It is the maximum time the device requires to automatically complete the internal write operation.

$\overline{\text{WR}}$ Controlled Write Cycle

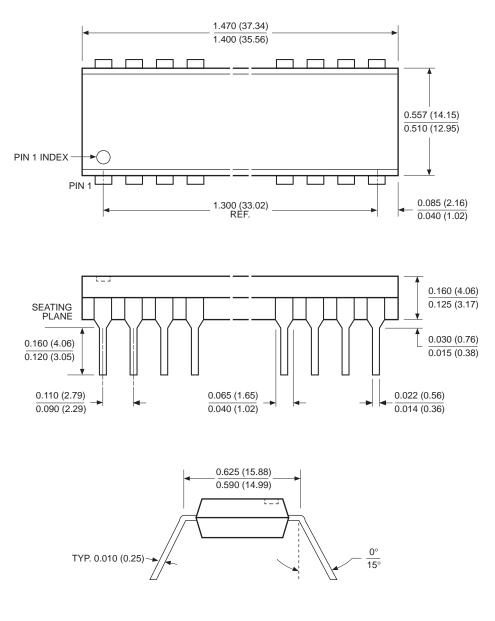
Symbol	Parameter	Min.	Max.	Units
tLHLL	ALE Pulse Width	80		ns
tavll	Address Setup Time	20		ns
tLLAX	Address Hold Time	30		ns
t _{DVWH}	Data Setup Time	50		ns
twhdx	Data Hold Time	30		ns
tELLL	Chip Enable Setup Time	7		ns
twLwH	WR Pulse Width	120		ns
twrs	WR Setup Time	30		ns
twrh	WR Hold Time	20		ns
tBLC	Byte Load Time (Page Write)	0.5	100	μs
twc (7)	Write Cycle Time		5	ms
		·	•	6539 PG

$\overline{\text{WR}}$ Controlled Write Timing Diagram



Note: (7) t_{WC} is the minimum cycle time to be allowed from the system perspective unless polling techniques are used. It is the maximum time the device requires to automatically complete the internal write operation.

PACKAGING INFORMATION

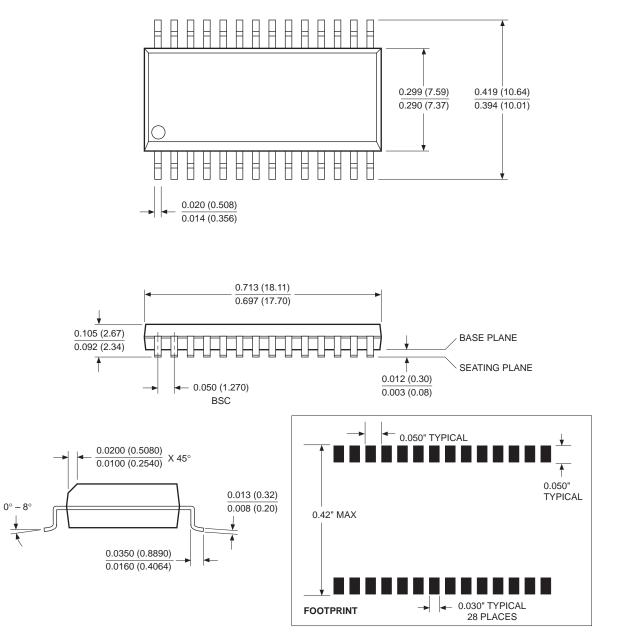


28-LEAD PLASTIC DUAL IN-LINE PACKAGE TYPE P

NOTE: 1. ALL DIMENSIONS IN INCHES (IN PARENTHESES IN MILLIMETERS) 2. PACKAGE DIMENSIONS EXCLUDE MOLDING FLASH

3926 FHD F04

PACKAGING INFORMATION



28-LEAD PLASTIC SMALL OUTLINE GULL WING PACKAGE TYPE S

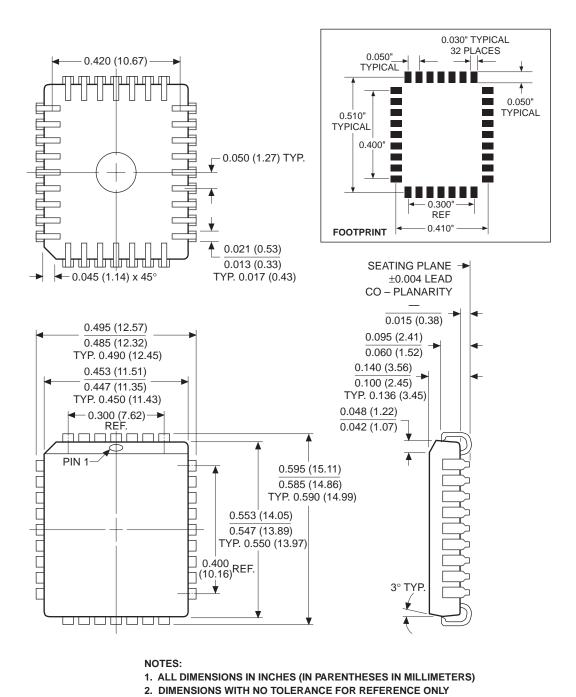
NOTES:

1. ALL DIMENSIONS IN INCHES (IN PARENTHESES IN MILLIMETERS)

2. FORMED LEAD SHALL BE PLANAR WITH RESPECT TO ONE ANOTHER WITHIN 0.004 INCHES

3926 FHD F17

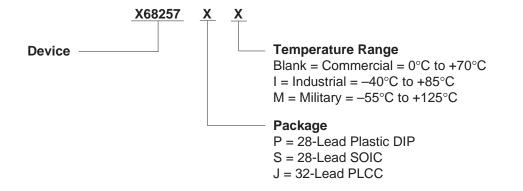
PACKAGING INFORMATION



32-LEAD PLASTIC LEADED CHIP CARRIER PACKAGE TYPE J

3926 FHD F13

ORDERING INFORMATION



LIMITED WARRANTY

Devices sold by Xicor, Inc. are covered by the warranty and patent indemnification provisions appearing in its Terms of Sale only. Xicor, Inc. makes no warranty, express, statutory, implied, or by description regarding the information set forth herein or regarding the freedom of the described devices from patent infringement. Xicor, Inc. makes no warranty of merchantability or fitness tor any purpose. Xicor, Inc. reserves the right to discontinue production and change specifications and prices at any time and without notice.

Xicor, Inc. assumes no responsibility for the use of any circuitry other than circuitry embodied in a Xicor, Inc. product. No other circuits, patents, licenses are implied.

US. PATENTS

Xicor products are covered by one or more of the following U.S. Patents: 4,263,664; 4,274,012; 4,300,212; 4,314,265; 4,326,134; 4,393,481; 4,404,475; 4,450,402; 4,486,769; 4,488,060; 4,520,461; 4,533,846; 4,599,706; 4,617,652; 4,668,932; 4,752,912; 4,829,482; 4,874,967; 4,883,976; 4,980,859; 5,012,132; 5,003,197; 5,023,694. Foreign patents and additional patents pending.

LIFE RELATED POLICY

In situations where semiconductor component failure may endanger life, system designers using this product should design the system with appropriate error detection and correction, redundancy and back-up features to prevent such an occurrence.

Xicor's products are not authorized for use as critical components in life support devices or systems.

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform, when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its satety or effectiveness.